

**Search Notes**

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10/618,402

Examiner

Shih-wen Hsieh

Applicant(s)/Patent under  
Reexamination

TEE ET AL.

Art Unit

2861

**SEARCHED**

Class	Subclass	Date	Examiner
updated	updated	3/23/2005	<i>SWH</i> SWH

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
347	29,32	3/23/2005	<i>SWH</i> SWH

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR